
**Optics and photonics — Optical
transfer function — Application —**

**Part 3:
Telescopes**

*Optique et instruments d'optique — Fonction de transfert optique —
Application —*

Partie 3: Télescopes

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Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

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This document was prepared by Technical Committee ISO/TC 172, *Optics and photonics*, Subcommittee SC 4, *Telescopic systems*.

This second edition cancels and replaces the first edition (ISO 9336-3:1994), which has been technically revised.

The main changes compared to the previous edition are as follows:

- update of the document based on the latest technical developments;
- [Annex A](#) regarding tests on components and sub-assemblies using azimuth scanning systems removed, due to lack of practical relevance;
- two new Annexes added regarding test methods using detector arrays and deriving an objective image quality criterion from the MTF.

A list of all parts in the ISO 9336 series can be found on the ISO website.

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